

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of
OKUNO et al.

Atty. Ref.: 1035-652

Serial No. To be assigned

TC/A.U.: unknown

Filed: August 25, 2006

Examiner: Unknown

For: SAMPLE TARGET HAVING SAMPLE SUPPORT SURFACE WHOSE
FACE IS TREATED, PRODUCTION METHOD THEREOF, AND MASS
SPECTROMETER USING THE SAMPLE TARGET

* * * * *

August 25, 2006

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

INFORMATION DISCLOSURE STATEMENT

As suggested by 37 C.F.R. 1.97, the undersigned attorney brings to the attention of the Patent and Trademark Office the references listed on the attached form PTO/SB/08a.

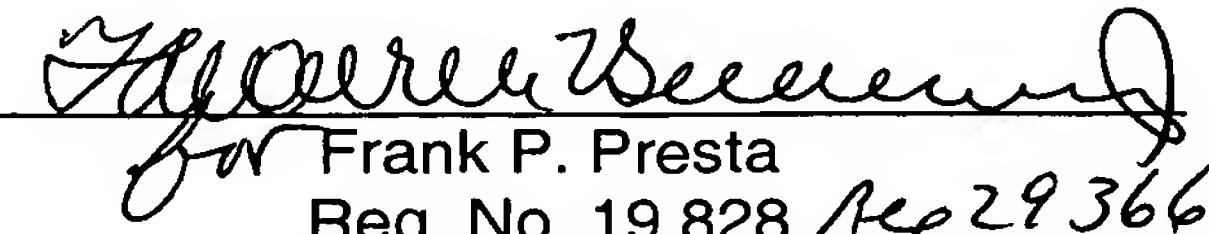
This is not to be construed as a representation that a search has been made or that no better prior art exists, or that a reference is relevant merely because cited.

The Examiner is requested to initial the attached form PTO/SB/08a and to return a copy of the initialed document to the undersigned as an indication that the attached references have been considered and made of record.

Respectfully submitted,

NIXON & VANDERHYTE P.C.

By:


for Frank P. Presta
Reg. No. 19,828 Reg 29366

FPP:alb
901 North Glebe Road, 11th Floor
Arlington, VA 22203-1808
Telephone: (703) 816-4000
Facsimile: (703) 816-4100

INFORMATION DISCLOSURE
CITATION

ATTY. DOCKET NO.

SERIAL NO.

1035-652

10/590822

To be assigned

APPLICANT

OKUNO et al.

(Use several sheets if necessary)

FILING DATE

TC/A.U.

August 25, 2006

unknown

U.S. PATENT DOCUMENTS

| *EXAMINER INITIAL | DOCUMENT NUMBER | DATE | NAME | CLASS | SUBCLASS | FILING DATE IF APPROPRIATE |
|----------------------|-----------------|---------|----------------|-------|----------|-------------------------------|
| | 6,288,390 B1 | 09/2001 | SIUZDAK et al. | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |
| | | | | | | |

FOREIGN PATENT DOCUMENTS

| DOCUMENT | DATE | COUNTRY | CLASS | SUBCLASS | TRANSLATION YES NO |
|--------------|---------|---------|-------|----------|-----------------------|
| 03/054915 A1 | 07/2003 | WO | | | |
| 2001-318217 | 11/2001 | JP | | | ABST |
| 2004-184137 | 07/2004 | JP | | | |
| 6-508472 | 09/1994 | JP | | | |
| 8-189917 | 07/1996 | JP | | | ABST |
| | | | | | |
| | | | | | |
| | | | | | |

OTHER DOCUMENTS (including Author, Title, Date, Pertinent pages, etc.)

| | |
|--|--|
| | International Search Report of PCT/JP2005/003055, mailed 31 May 2005 |
| | "Desorption-Ionization Mass Spectrometry on Porous Silicon", (Jing WEI et al., Nature, Vol.399, May 1999, pp.243-246) |
| | "Porous Silicon as a Versatile Platform for Laser Desorption/Ionization Mass Spectrometry", (Zhouxin SHEN et al., Analytical Chemistry, 73, 2001, pp.612-619) |
| | "New Desorption Strategies for the Mass Spectrometric Analysis of Macromolecules", (T. W. HUTCHENS et al., Rapid Communications in Mass Spectrometry, Vol. 7, 1993, pp.576-580) |
| | "A Self-Assembled Matrix Monolayer for UV-MALDI Mass Spectrometry", (Stephane Mouradian et al., J. Am. Chem. Soc., 118, 1996, pp.8639-8645) |
| | "Laser Desorption/Ionization Time-of Flight Mass Spectrometry on Sol—Gel-Derived 2,5-Dihydroxybenzoic Acid Film", (Ya-Shiuan LIN et al., Analytical Chemistry, Vol. 74, No. 22, November 2002, pp.5793-5798) |
| | "High Sensitivity and Analyte Capture with Desorption/Ionization Mass Spectrometry on Silylated Porous Silicon", (Sunia A. TRAUGER et al., Analytical Chemistry, Vol. 76, No. 15, August 2004, pp.4484-4489) |
| | "Use of a Non-porous Polyurethane Membrane as a Sample Support for Matrix-assisted Laser Desorption/Ionization Time-of-flight Mass Spectrometry of Peptides and Proteins", (Mark E. McComb et al., Rapid Communications in Mass Spectrometry, Vol. 11, 1997, pp.1716-1722) |
| | "Signal Enhancement in Matrix-assisted Laser Desorption/Ionization by Doping with Cu(II) Chloride", (Maxim DASHTIEV et al., (Letter to the Editor) Rapid Communications in Mass Spectrometry, Vol. 19, 2005, pp.289-291) |
| | "UV Laser Desorption/Ionization on Submicrometer Order Structures", (Shoji OKUNO et al., The 52 nd Annual Conference on Mass Spectrometry, June 2004, pp.118-119, 1-P-34) |
| | |
| | |
| | |

*Examiner

Date Considered

Examiner: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to application.